



SOFT Microscopy Centre –

Soft Microscopy Centre – Network meeting spring 2024

Location: RISE, Brinellgatan 4, Borås, Sweden, room: DaVinci, Hus 1 (entrance via Reception)

Theme: Chemical imaging and surface characterisation

PROGRAM 16 MAY 2024

- | | |
|---------------|---|
| 09.30 – 10.00 | Coffee and registration |
| 10.00 – 10.10 | Welcome to the microscopy network meeting
<i>Eva Olsson, Chalmers, Torben Nilsson Pingel, Niklas Lorén and Mats Stading, RISE</i> |
| 10.15 – 10.45 | Introduction to TOF-SIMS
<i>Peter Sjövall, RISE</i> |
| 10.50 – 11.20 | NanoSIMS – Isotopic and Trace Element Analysis at High Spatial Resolution
<i>Per Malmberg, Chalmers</i> |
| 11.25 – 12.10 | ToF-SIMS for Industrial Applications
<i>Birgit Hagenhoff, Tascon (remote)</i> |
| 12.10 – 13.20 | Lunch |
| 13.20 – 14.10 | Demonstration of RISE new TOF-SIMS
<i>Peter Sjövall, RISE</i> |
| 14.10 – 14.55 | Labtour (TOF-SIMS, SEM) |
| 14.55 – 15.20 | Coffee break |
| 15.20 – 15.50 | Introduction to X-ray Photoelectron Spectroscopy (XPS) – a strong complement to TOF-SIMS
<i>Marie Ernstsson, RISE</i> |
| 15.55 – 16.25 | Advanced photoelectron spectroscopy for soft and energy materials
<i>Julia Maibach, Chalmers</i> |
| 16.25 | Concluding remarks |
| 16.30 | End of meeting |

[SIGN UP](#)